STANDARDS MALAYSIA
ACCREDITED LABORATORY

MS ISO/IEC 17025

Certificate of Accreditation

No: SAMM 549
(Issue 3, 21 February 2013 replacement of SAMM 549 dated 27 August 2012)

Valid until: 10 February 2015

This is to certify that

CLMO TECHNOLOGY (PENANG) SDN. BHD.
BAYAN LEPAS, PENANG
MALAYSIA
(FIELD OF CALIBRATION: TEMPERATURE)
(FIELD OF TESTING: MECHANICAL)

has been granted accreditation in respect of the scope of accreditation described in the SCHEDULE attached, subject to the terms and conditions governing the *Skim Akreditasi Makmal Malaysia* (SAMM), the Laboratory Accreditation Scheme of Malaysia.

"This laboratory is accredited in accordance with the recognised International Standard ISO/IEC 17025:2005. This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory quality management system (refer joint ISO-ILAC-IAF Communiqué dated January 2009)".

Issuance of this certificate is governed by Section 16 Subsection (2) and (3) of Standards of Malaysia Act 1996, (Act 549).

Jabatan Standard Malaysia • Department of Standards Malaysia • STANDARDS MALAYSIA

(FADILAH BAHARIN)
Director General
Department of Standards Malaysia

Date of issue: 21 February 2013

Issue date: 21 February 2013
Valid until: 10 February 2015

MS ISO/IEC 17025

NO: SAMM 549

(Issue 4, 21 February 2013 replacement of SAMM 549 dated 21 November 2012)

LABORATORY LOCATION:
(PERMANENT LABORATORY)

CLMO TECHNOLOGY (PENANG) SDN. BHD.
NO. 6, LINTANG BAYAN LEPAS 2
TAMAN PERINDUSTRIAN BAYAN LEPAS FASA 4
11900 BAYAN LEPAS
PENANG, MALAYSIA

This laboratory accredited under *Skim Akreditasi Makmal Malaysia* (SAMM) meets the requirements of MS ISO/IEC 17025:2005 'General requirements for competence of testing and calibration laboratories'. This Malaysian Standards is identical with ISO/IEC 17025:2005 published by the International Organization for Standardization (ISO).

*** The expanded uncertainties are based on an estimated confidence probability of not less than 95% and have a coverage factor of k=2 unless stated otherwise.**

FIELD OF CALIBRATION: **TEMPERATURE**

SITE CALIBRATION: **CATEGORY III**

SCOPE OF ACCREDITATION:

Instrument Calibrated/ Measurement Parameter	Range	Calibration and Measurement Capability Expressed as an Uncertainty (±)*	Remarks
Temperature Enclosure	30 °C to 300 °C	0.8 °C	Temperature fluctuation range based on JTM K-05:2000 clause 6.3
	-80 °C to 200 °C	0.5 °C	Temperature fluctuation range based on JTM K-01:1998 clause 6.3
Temperature & Humidity Chamber	-80 °C to 150 °C (without humidity)	0.5 °C	Temperature fluctuation based on JTM K-01:1998 clause 6.3
	10 °C to 85 °C 5 %RH to 98 %RH	0.5 °C 2.5 %RH	Temperature and humidity fluctuation based on JTM K-01:1998 clause 6.3
Temperature & Humidity Room	-40 °C to 80 °C (without humidity)	0.5 °C	Temperature fluctuation only based on JTM K-03:2001 clause 6.3
	10 °C to 80 °C 5 %RH to 98 %RH	0.5 °C 2.5 %RH	Temperature and humidity fluctuation only based on JTM K-03:2001 clause 6.3

Signatories:

1. **Teng Thiam Wan**
2. **Pung Chee Hon**

NO: SAMM 549

(Issue 4, 21 February 2013 replacement
of SAMM 549 dated 21 November 2012)

FIELD OF TESTING: **MECHANICAL (ENVIRONMENTAL TESTING)**

SCOPE OF ACCREDITATION:

Materials/ Products Tested	Type of Test/ Properties Measured/ Range of Measurement	Standard Test Method/ Equipment/Techniques
Semiconductor, printed circuit board assembly, finished electrical and electronic product	Change of temperature Max temperature = 150 °C Min temperature = -65 °C	IEC 60068-2-14:2009 (Test Na and Test Nb)
	Damp heat cyclic 10 °C to 85 °C 20 %RH to 98 %RH	IEC 60068-2-30:2008
	Dry heat 30 °C to 200 °C	MS IEC 60068-2-2:2007 (Test Bb)
	Damp heat, steady state 10 °C to 85 °C 20 %RH to 98 %RH	MS IEC 60068-2-78:2008

Signatories:

1. **Teng Thiam Wan**
2. **Pung Chee Hon**